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SJ

**INDUSTRY STANDARD OF THE
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**Non-contact measurement method for the resistivity of
semi-insulating semiconductor wafer**

半绝缘半导体晶片电阻率的无接触测量方法

(English Translation)

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What this standard covers

This Standard specifies the method for non-contact measurement of semi-insulating semiconductor wafer resistivity. This Standard applies to the measurement of semi-insulating gallium arsenide, indium phosphide, silicon carbide and other high-impedance semiconductor material resistivity, the resistivity measurement range is $10^{-5} \Omega \cdot \text{cm} \sim 10^{12} \Omega \cdot \text{cm}$

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